

Notice of References Cited	Application/Control No. 10/068,414	Applicant(s)/Patent Under Reexamination FUJII ET AL.	
	Examiner Beniyam Menberu	Art Unit 2626	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0097411 A1	07-2002	Roche et al.	358/1.9
*	B	US-4,814,894	03-1989	Yoshida, Takehiro	358/426.02
*	C	US-5,488,483	01-1996	Murayama, Masahiro	382/251
*	D	US-2003/0218762 A1	11-2003	Edwards et al.	358/1.2
*	E	US-2002/0015182 A1	02-2002	Akiyama et al.	358/1.15
*	F	US-6,590,673	07-2003	Kadowaki, Toshihiro	358/1.15
*	G	US-6,614,551	09-2003	Peek, Gregory A.	358/1.15
*	H	US-6,437,881	08-2002	Baba et al.	358/434
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000105816 A	04-2000	Japan	KUSUNOKI, TADAKAZU	G06T 01/00
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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